

**Search Notes**

Application/Control No.

10/823,550

Examiner

Terrence R. Willoughby

Applicant(s)/Patent under  
Reexamination

CHO ET AL.

Art Unit

2836

**SEARCHED**

Class	Subclass	Date	Examiner
361	234	2/7/2006	TRW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
L1: Wafer same (plate platen) L2: 1 same chuck L3: 2 same voltage same electrodes	2/8/2006	TRW
L4: 3 same ring	2/8/2006	TRW
L5: 4 same (gas) same power	2/8/2006	TRW
L6: 3 same (guide)	2/8/2006	TRW
L7: 2 same voltage (first near electrode\$1) same (second near electrode\$1)	2/8/2006	TRW
L8: 2 same (gas power) same source	2/8/2006	TRW
L9: 8 same (dielectric)	2/8/2006	TRW